

# MBN1500E33E2

Silicon N-channel IGBT 3300V E2 version

## FEATURES

- \* Soft switching behavior & low conduction loss:  
Soft low-injection punch-through High conductivity IGBT.
- \* Low driving power due to low input capacitance MOS gate.
- \* Low noise recovery: Ultra soft fast recovery diode.
- \* High thermal fatigue durability:  
( $\Delta T_c=70K$ ,  $N>30,000$ cycles)  
AlSiC base-plate/AlN substrate

## ABSOLUTE MAXIMUM RATINGS ( $T_c=25^\circ C$ )

Item	Symbol	Unit	MBN1500E33E2
Collector Emitter Voltage	$V_{CES}$	V	3,300
Gate Emitter Voltage	$V_{GES}$	V	$\pm 20$
Collector Current	DC	$I_C$	1,500 ( $T_c=95^\circ C$ )
	1ms	$I_{CP}$	3,000
Forward Current	DC	$I_F$	1,500
	1ms	$I_{FM}$	3,000
Junction Temperature	$T_j$	$^\circ C$	-40 ~ +150
Storage Temperature	$T_{stg}$	$^\circ C$	-50 ~ +125
Isolation Voltage	$V_{ISO}$	$V_{RMS}$	6,000(AC 1 minute)
Screw Torque	Terminals (M4/M8)	-	2/15 (1)
	Mounting (M6)	-	6 (2)

Notes: (1) Recommended Value  $1.8 \pm 0.2/15^{+0}_{-3} N \cdot m$  (2) Recommended Value  $5.5 \pm 0.5 N \cdot m$

## ELECTRICAL CHARACTERISTICS

Item	Symbol	Unit	Min.	Typ.	Max.	Test Conditions
Collector Emitter Cut-Off Current	$I_{CES}$	mA	-	-	12	$V_{CE}=3,300V, V_{GE}=0V, T_j=25^\circ C$
Gate Emitter Leakage Current	$I_{GES}$	nA	-500	-	+500	$V_{CE}=\pm 20V, V_{GE}=0V, T_j=25^\circ C$
Collector Emitter Saturation Voltage	$V_{CE(sat)}$	V	2.5	2.95	3.5	$I_C=1,500A, V_{GE}=15V, T_j=125^\circ C$
			-	3.1	-	$I_C=1,500A, V_{GE}=15V, T_j=150^\circ C$
Gate Emitter Threshold Voltage	$V_{GE(TO)}$	V	5.5	6.3	7.5	$V_{CE}=10V, I_C=1,500mA, T_j=25^\circ C$
Input Capacitance	$C_{ies}$	nF	-	195	-	$V_{CE}=10V, V_{GE}=0V, f=100kHz, T_j=25^\circ C$
Internal Gate Resistance	$R_{ge}$	$\Omega$	-	1.0	-	$V_{CE}=10V, V_{GE}=0V, f=100kHz, T_j=25^\circ C$
Switching Times	Rise Time	$t_r$	1.6	2.0	2.6	$V_{CC}=1,650V, I_C=1,500A$
	Turn On Time	$t_{on}$	2.0	3.0	3.7	$L_s=100nH$
	Fall Time	$t_f$	0.9	1.7	2.6	$R_G=2.7\Omega/2.7\Omega, C_{GE}=330nF$ (3)
	Turn Off Time	$t_{off}$	2.7	4.4	5.5	$V_{GE}=\pm 15V, T_j=125^\circ C$
Peak Forward Voltage Drop	$V_{FM}$	V	2.2	2.6	3.0	$I_F=1,500A, V_{GE}=0V, T_j=125^\circ C$
			-	2.6	-	$I_F=1,500A, V_{GE}=0V, T_j=150^\circ C$
Reverse Recovery Time	$t_{rr}$	$\mu s$	0.2	0.8	1.2	$V_{CC}=1,650V, I_F=1,500A, L_s=100nH, T_j=125^\circ C$
Turn On Loss	$E_{on(10\%)}$	J/P	-	2.9	3.6	$T_j=125^\circ C$
	$E_{on(full)}$		-	3.2	-	$T_j=150^\circ C$
Turn Off Loss	$E_{off(10\%)}$	J/P	-	2.2	2.6	$T_j=125^\circ C$
	$E_{off(full)}$		-	2.4	-	$T_j=150^\circ C$
Reverse Recovery Loss	$E_{rr(10\%)}$	J/P	-	1.4	1.9	$T_j=125^\circ C$
	$E_{rr(full)}$		-	1.7	-	$T_j=150^\circ C$

Notes:(3)  $R_G$  and  $C_{GE}$  value are the test condition's value for evaluation of the switching times, not recommended value.  
Please, determine the suitable  $R_G$  value after the measurement of switching waveforms (overshoot voltage, etc.) with appliance mounted.

- \* Please contact our representatives at order.
- \* For improvement, specifications are subject to change without notice.
- \* For actual application, please confirm this spec sheet is the newest revision.

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## THERMAL CHARACTERISTICS

Item		Symbol	Unit	Min.	Typ.	Max.	Conditions
Thermal Impedance	IGBT	Rth(j-c)	K/W	-	-	0.0078	Junction to case
	FWD	Rth(j-c)		-	-	0.0156	
Contact Thermal Impedance		Rth(c-f)	K/W	-	0.005	-	Case to fin ( $\lambda_{grease}=1W/(m \cdot K)$ , heat-sink flatness $\leq 50\mu m$ )

## MODULE MECHANICAL CHARACTERISTICS

Item		Unit	Characteristics	Conditions
Weight		g	1,300	
Stray inductance in module	LS(CM-EM)	nH	12	Collector-main to Emitter-main
	LS(ES-EM)		49	Emitter-sense to Emitter-main
	LS(CM-CS)		56	Collector-main to Collector sense
Terminal Resistance	R <sub>Terminal</sub>	mΩ	0.09	Collector-main to Emitter-main
Comparative Tracking Index (CTI)			600	
Module base plate Material			Al-SiC	
Baseplate Thickness		mm	5	
Insulation plate Material			Al N	
Terminal Surface treatment			Ni plating	
Case Material			Poly-Phenilene Sulfide	
Fire and Smoke Category			I2 / F3	NFF 16-102

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## DEFINITION OF TEST CIRCUIT

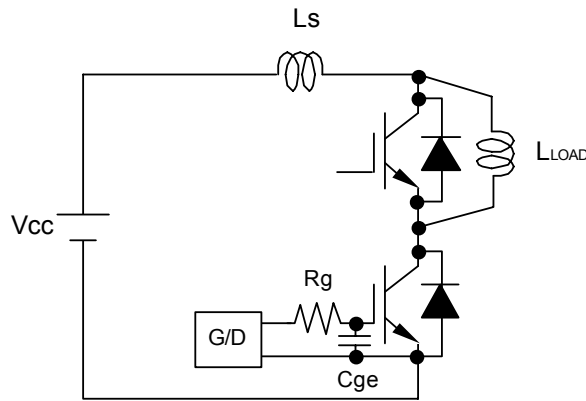


Fig.1 Switching test circuit

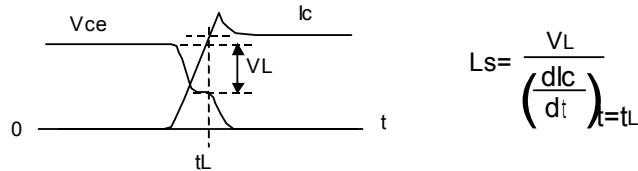


Fig.2 Definition of stray inductance

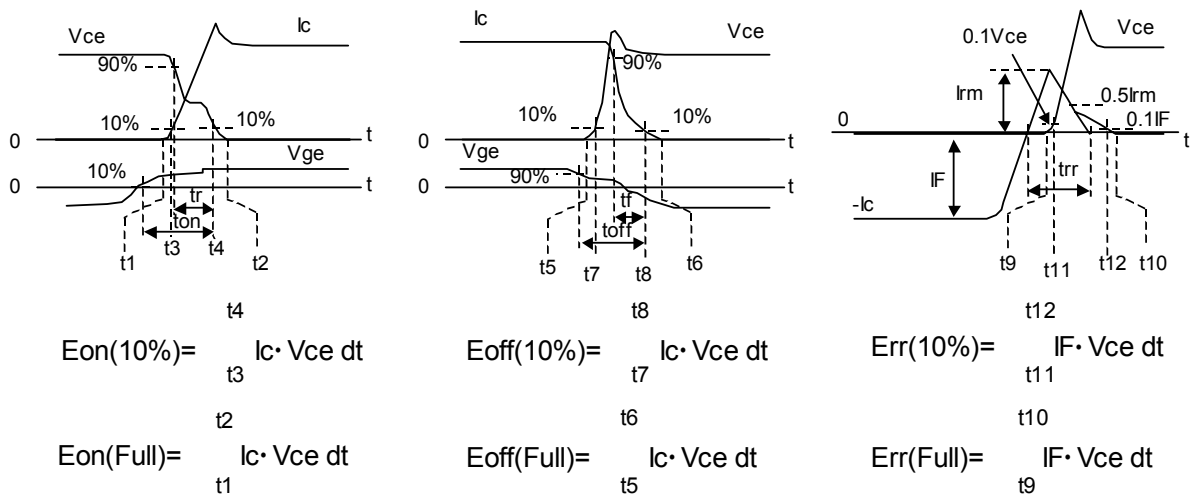
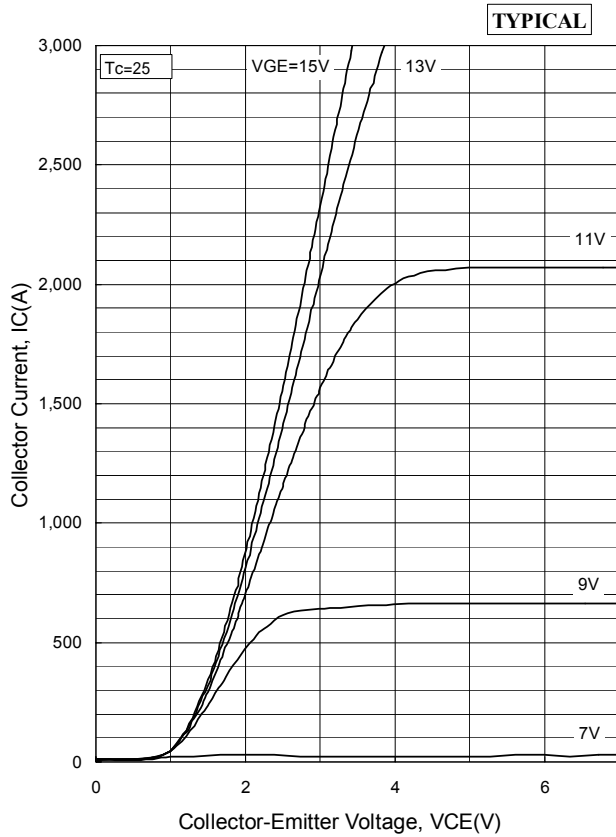


Fig.3 Definition of switching loss

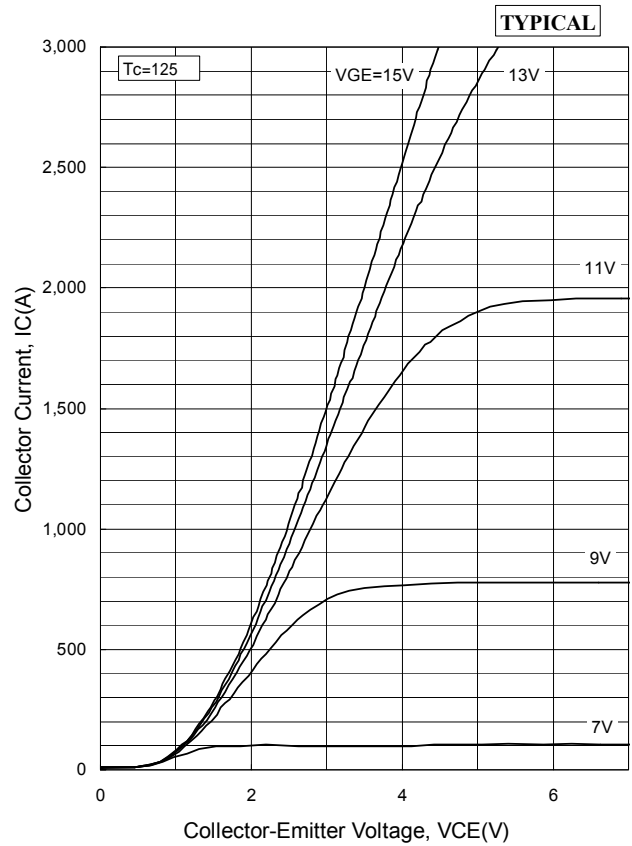
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## CHARACTERISTICS CURVE

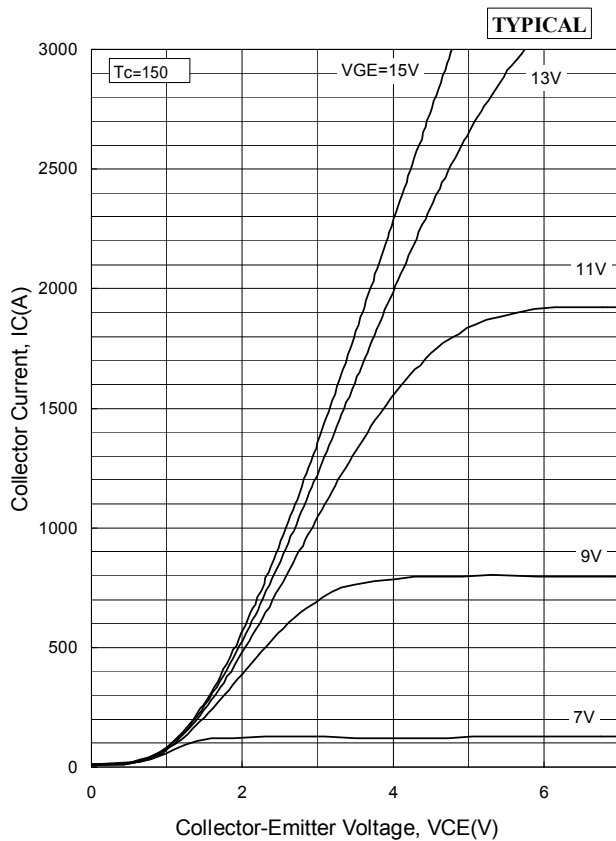
### STATIC CHARACTERISTICS



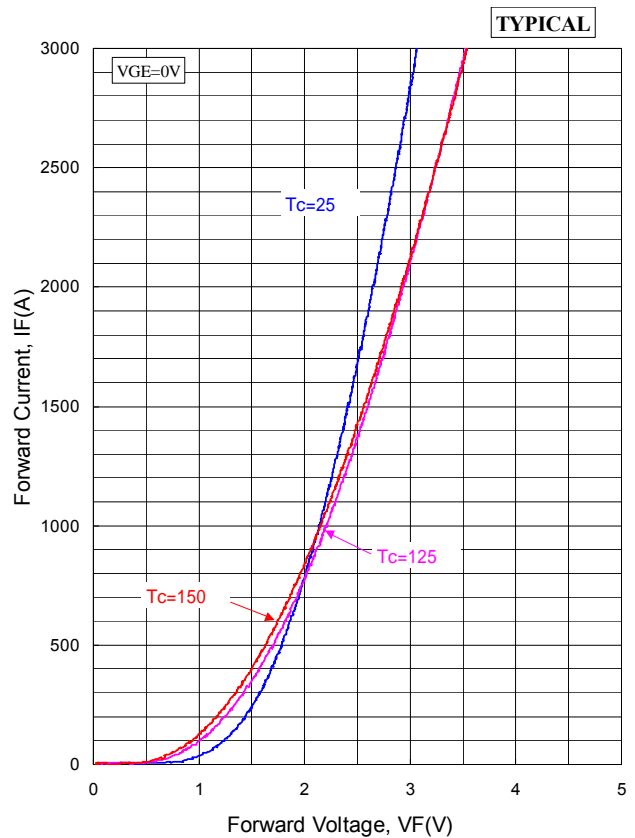
Collector Current vs. Collector to Emitter Voltage



Collector Current vs. Collector to Emitter Voltage



Collector Current vs. Collector to Emitter Voltage

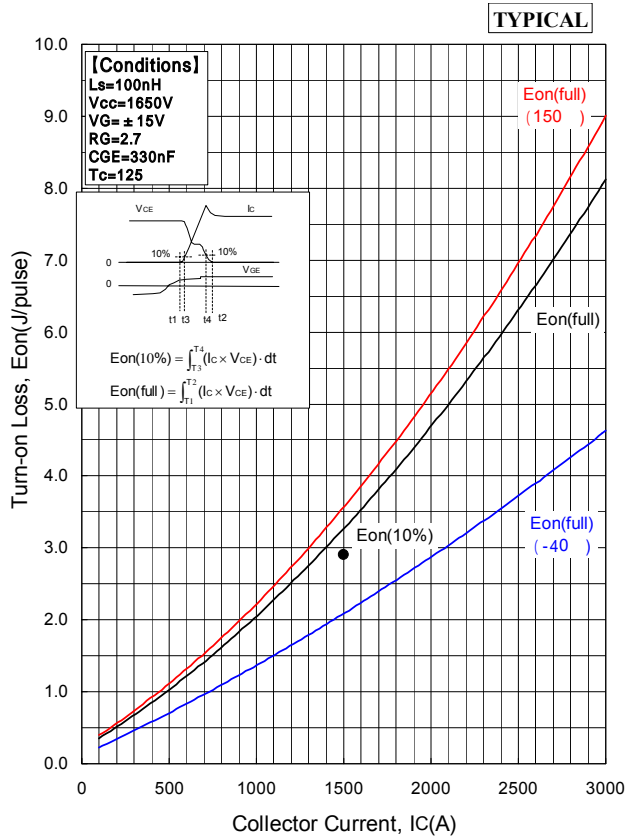


Forward Voltage of free-wheeling diode

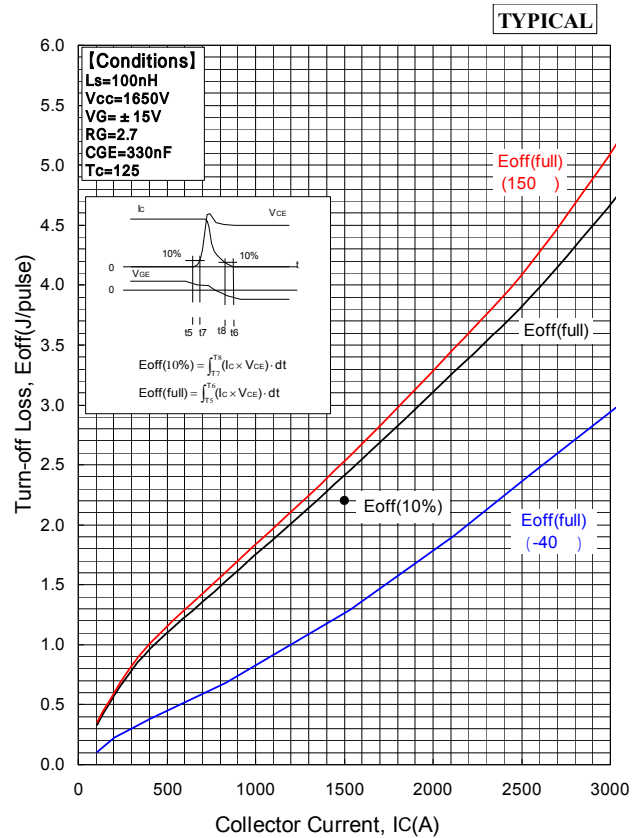
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## DYNAMIC CHARACTERISTICS

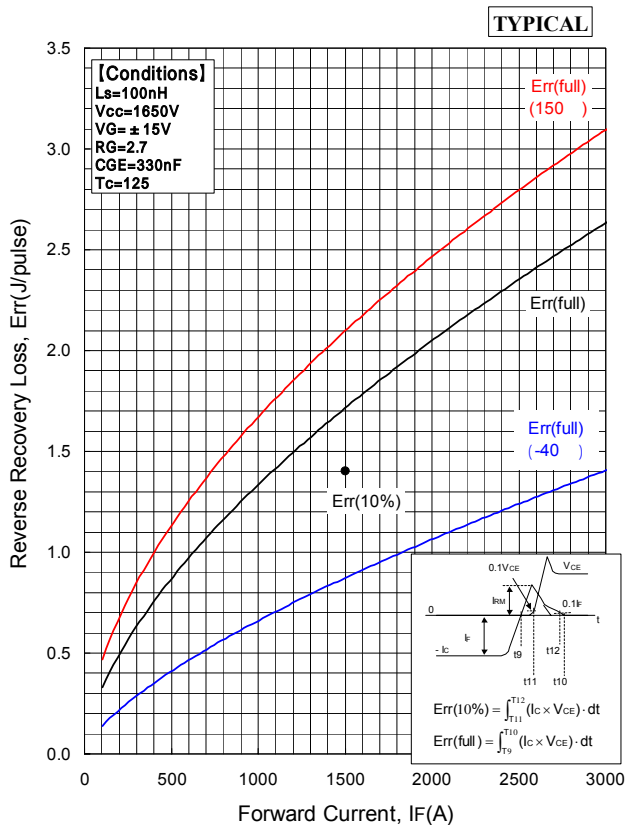
### DEPENDENCE OF CURRENT



Turn-on Loss vs. Collector Current

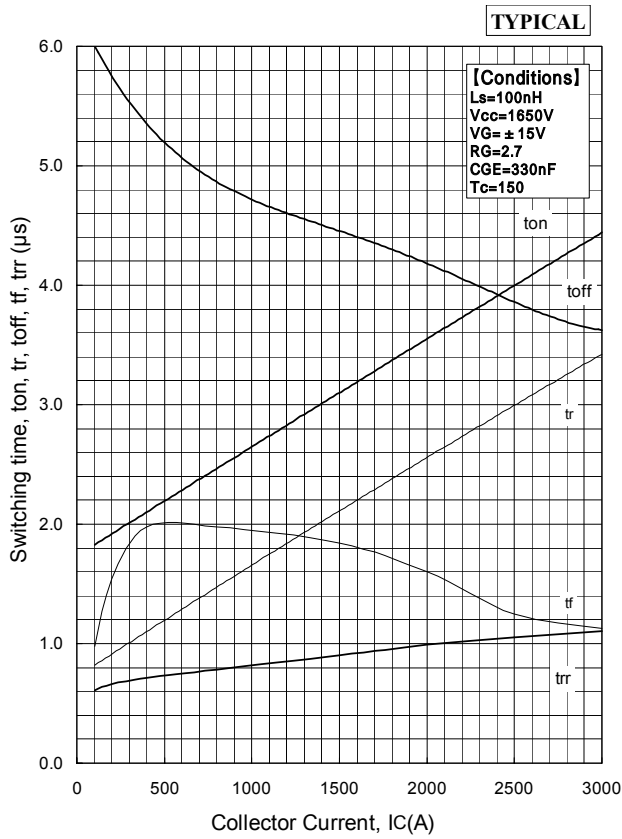


Turn-off Loss vs. Collector Current

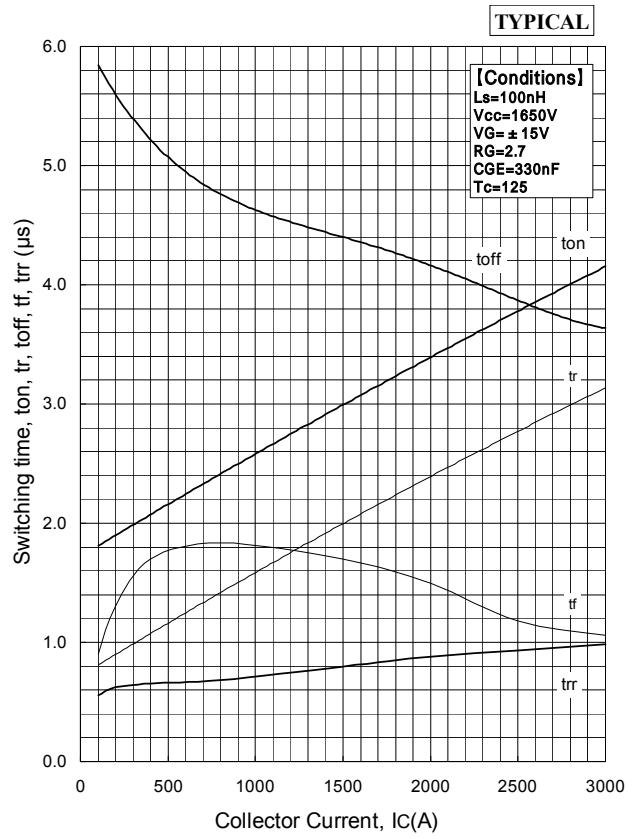


Recovery Loss vs. Forward Current

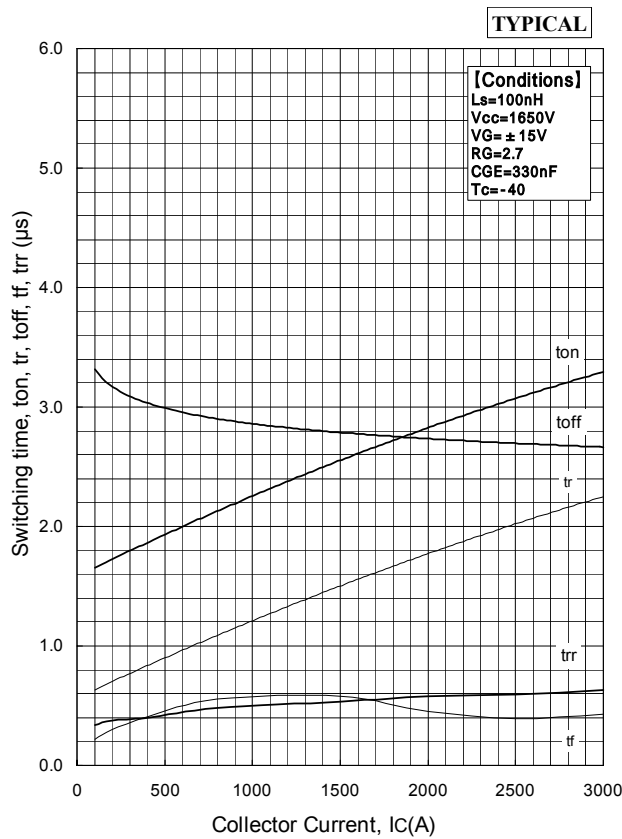
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Switching time vs. Collector current



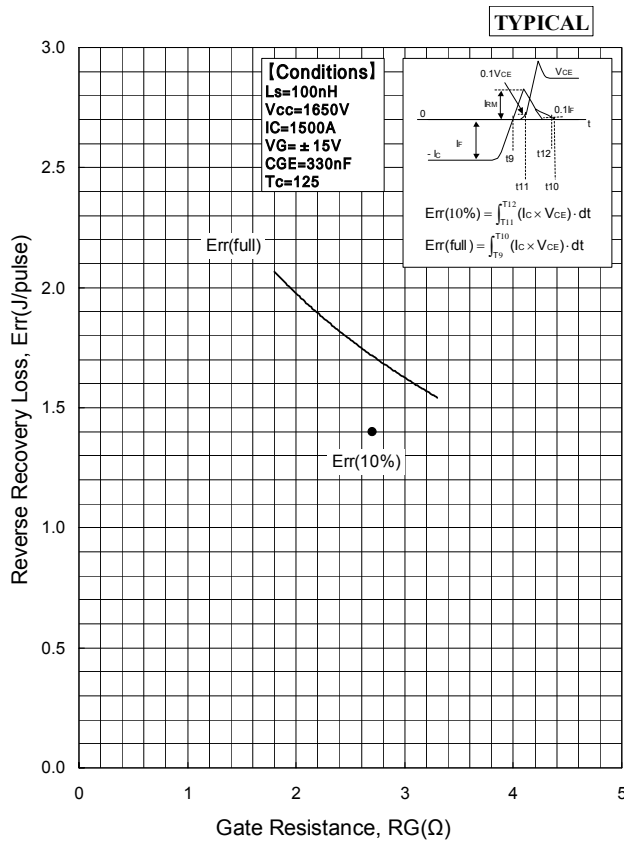
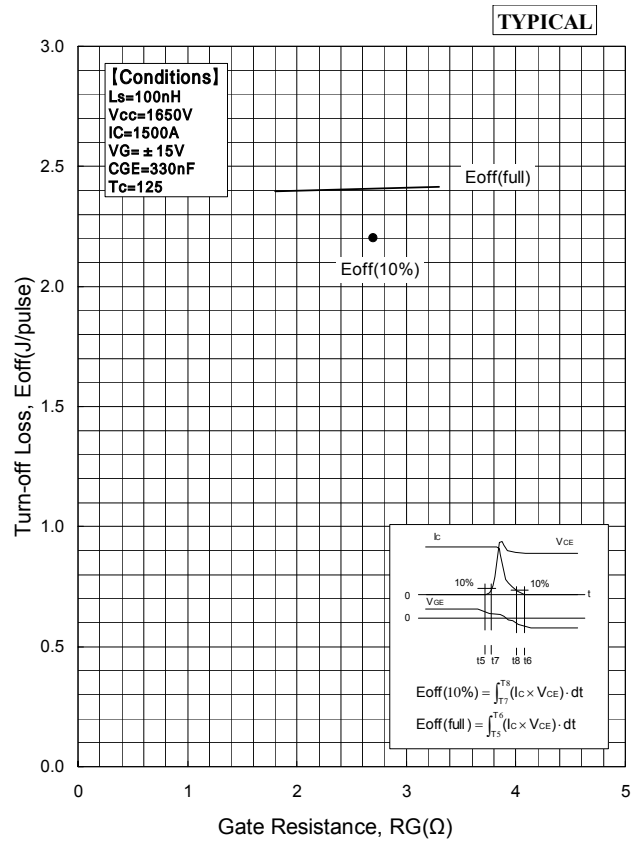
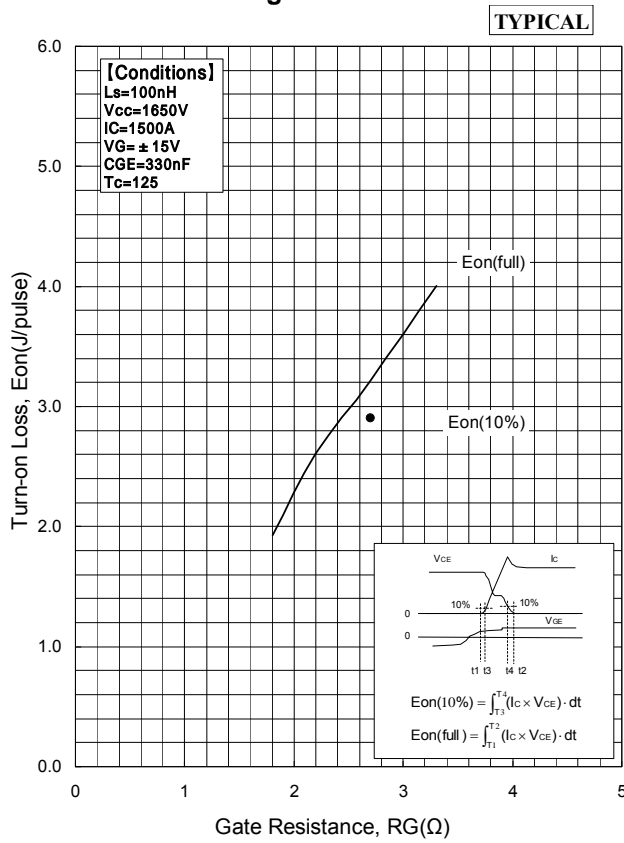
Switching time vs. Collector current



Switching time vs. Collector current

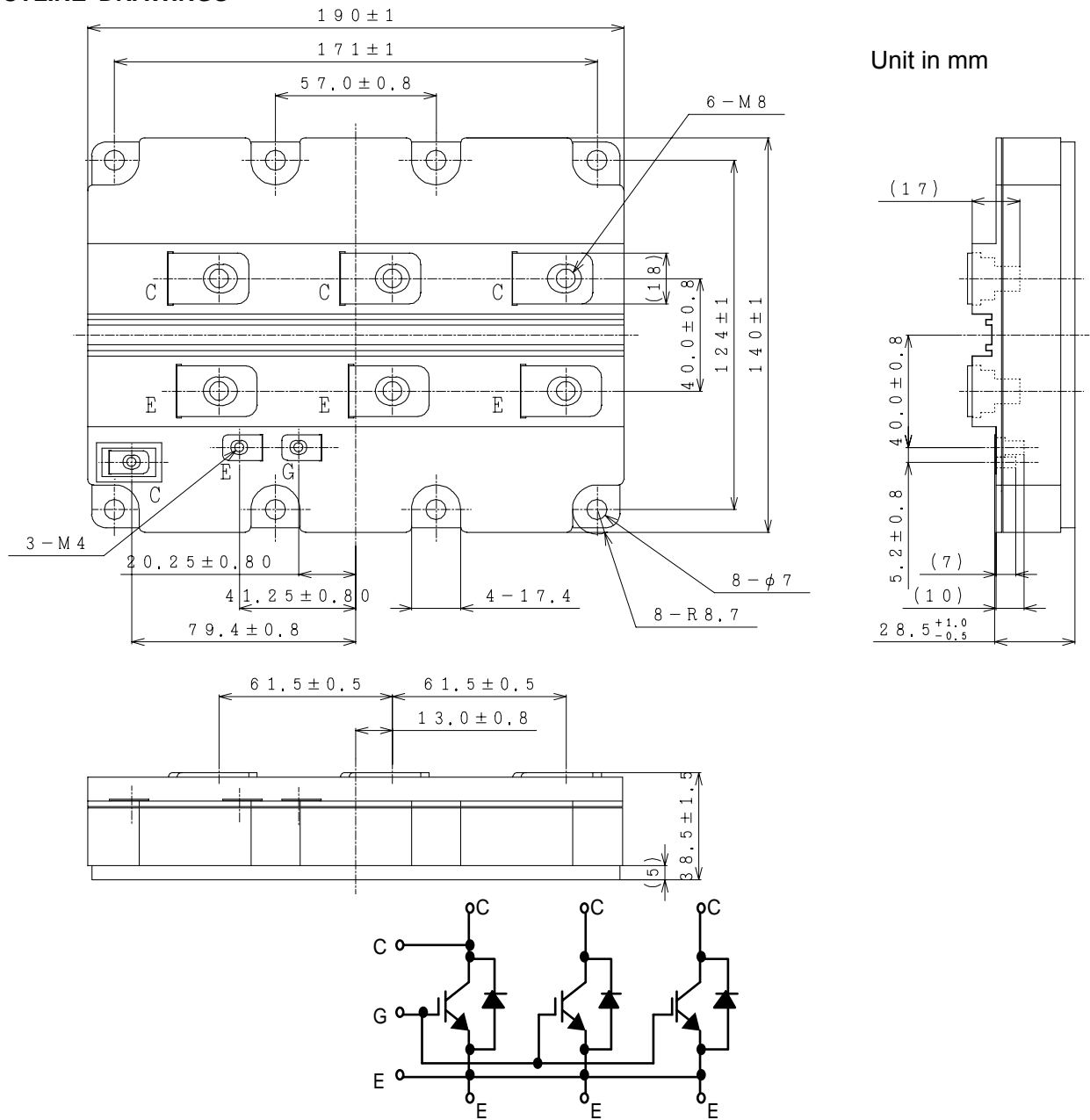
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## DEPENDENCE OF Rg



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## OUTLINE DRAWINGS



Unit in mm

Circuit diagram

### Material declaration

Please note the following materials are contained in the product, in order to keep characteristic and reliability level.

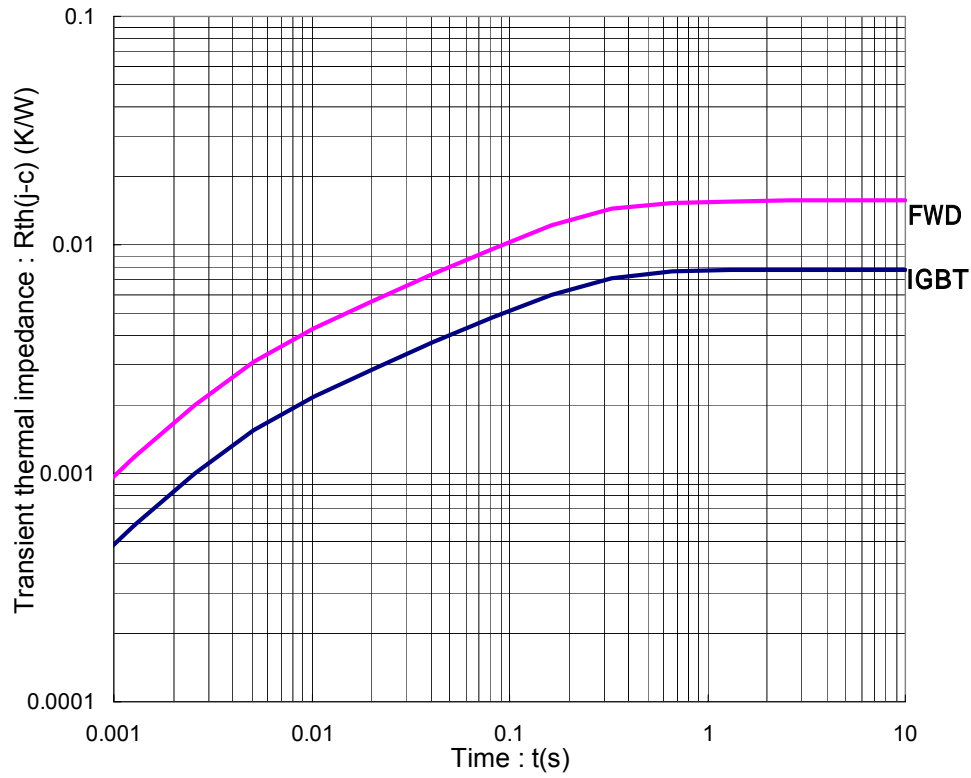
Material	Contained part
Lead (Pb) and its compounds	Solder



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## TRANSIENT THERMAL IMPEDANCE

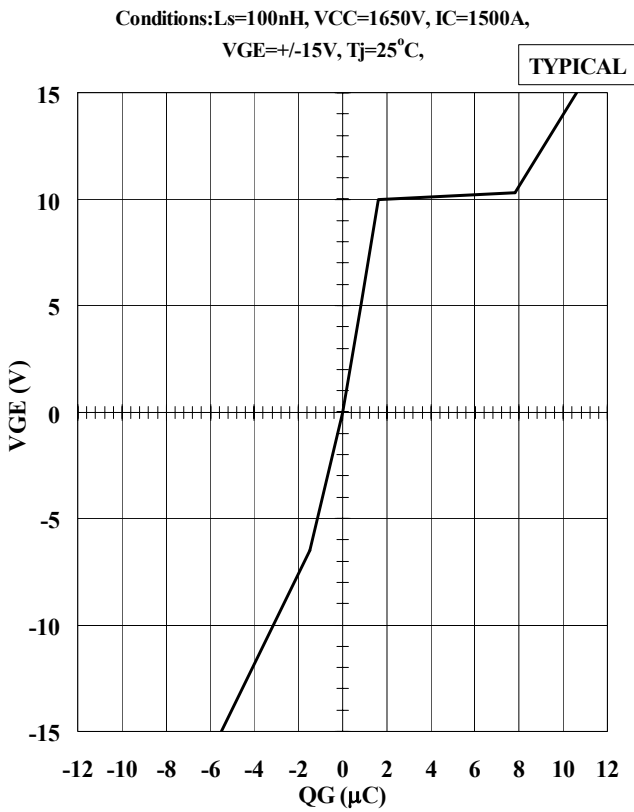
Maximum



**Transient Thermal Impedance Curve**

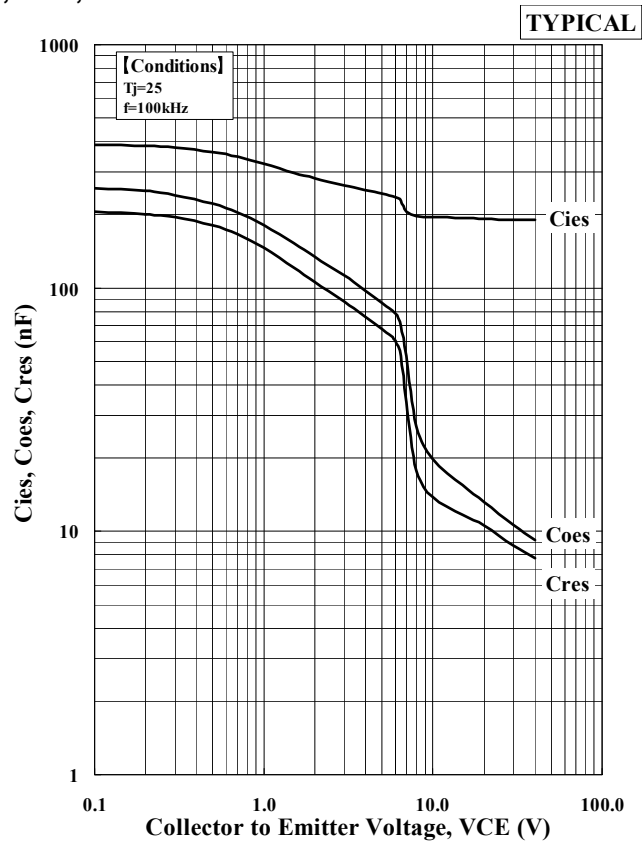
# MBN1500E33E2

## QG-VG CURVE



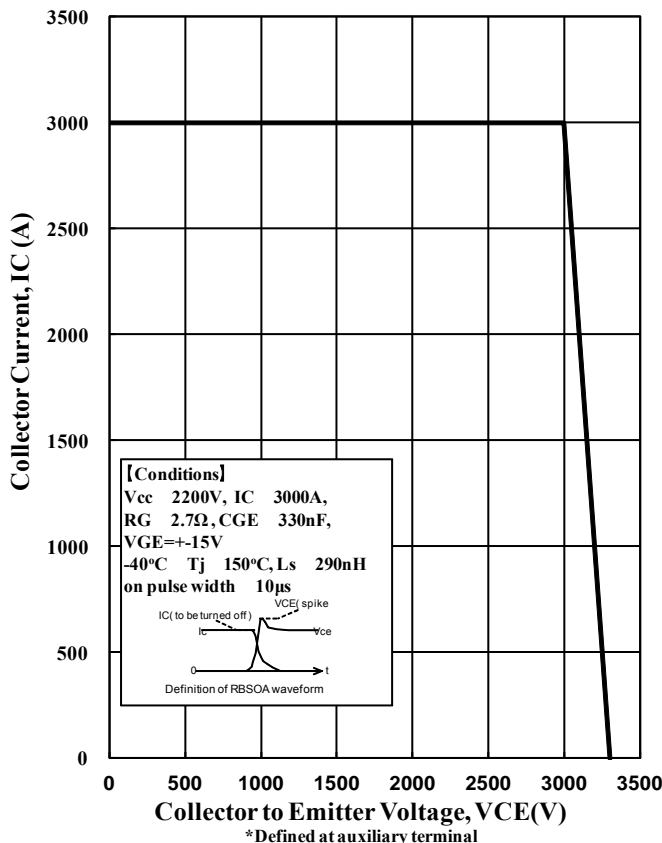
QG-VGE curve

## Cies, Coes, Cres Curve

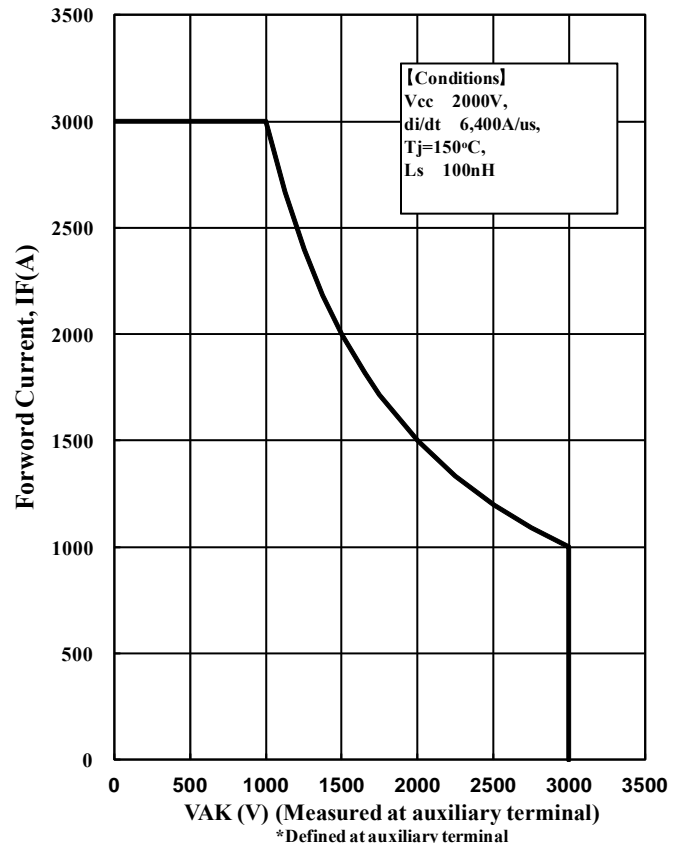


Capacitance vs. Collector to Emitter Voltage

## Safe operation area



Reverse bias Safe operation area(RBSOA)



Reverse recovery operation area(RecSOA)

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## HITACHI POWER SEMICONDUCTORS

### Notices

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2. Please be sure to read "Precautions for Safe Use and Notices" in the individual brochure before use.
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